



# CY7C144 CY7C145

## Features

- True Dual-Ported memory cells that allow simultaneous reads of the same memory location
- 8K x 8 organization (CY7C144)
- 8K x 9 organization (CY7C145)
- 0.65-micron CMOS for optimum speed/power
- High-speed access: 15ns
- Low operating power: I<sub>CC</sub> = 160 mA (max.)
- Fully asynchronous operation
- Automatic power-down
- TTL compatible
- · Master/Slave select pin allows bus width expansion to 16/18 bits or more
- Busy arbitration scheme provided
- · Semaphores included to permit software handshaking between ports
- INT flag for port-to-port communication
- Available in 68-pin PLCC, 64-pin and 80-pin TQFP
- Pb-Free packages available

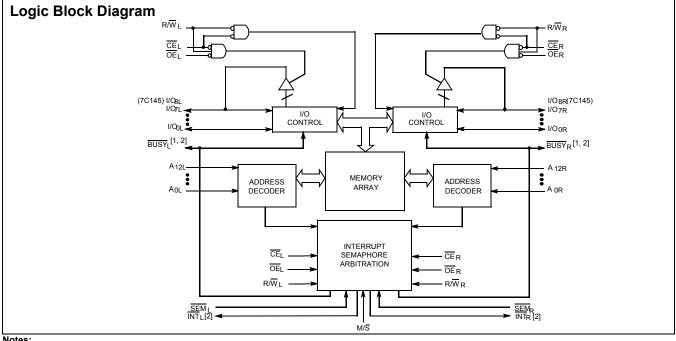
#### Functional Description

The CY7C144 and CY7C145 are high-speed CMOS 8K x 8 and 8K x 9 dual-port static RAMs. Various arbitration schemes

# 8K x 8/9 Dual-Port Static RAM with SEM, INT, BUSY

are included on the CY7C144/5 to handle situations when multiple processors access the same piece of data. Two ports are provided permitting independent, asynchronous access for reads and writes to any location in memory. The CY7C144/5 can be utilized as a standalone 64/72-Kbit dual-port static RAM or multiple devices can be combined in order to function as a 16/18-bit or wider master/slave dual-port static RAM. An M/S pin is provided for implementing 16/18-bit or wider memory applications without the need for separate master and slave devices or additional discrete logic. Application areas include interprocessor/multiprocessor designs, buffering, communications status and dual-port video/graphics memory.

Each port has independent control pins: chip enable (CE), read or write enable (R/W), and output enable (OE). Two flags, BUSY and INT, are provided on each port. BUSY signals that the port is trying to access the same location currently being accessed by the other port. The interrupt flag (INT) permits communication between ports or systems by means of a mail box. The semaphores are used to pass a flag, or token, from one port to the other to indicate that a shared resource is in use. The semaphore logic is comprised of eight shared latches. Only one side can control the latch (semaphore) at any time. Control of a semaphore indicates that a shared resource is in use. An automatic power-down feature is controlled independently on each port by a chip enable ( $\overline{CE}$ ) pin or SEM pin.



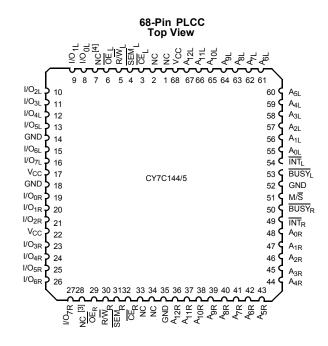
Notes

1. BUSY is an output in master mode and an input in slave mode.

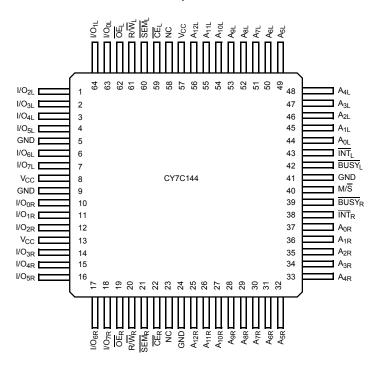
2. Interrupt: push-pull output and requires no pull-up resistor.

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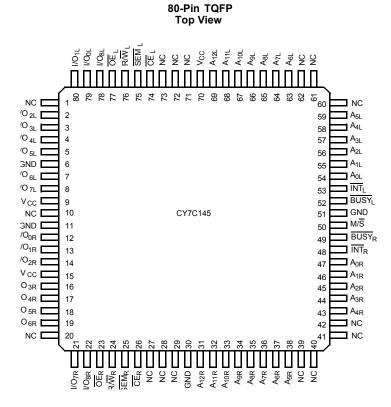
Notes:

3.  $I/O_{8R}$  on the CY7C145.

4. I/O<sub>8L</sub> on the CY7C145.



## Pin Configurations (continued)



## **Pin Definitions**

Left Port	Right Port	Description
I/O <sub>0L-7L(8L)</sub>	I/O <sub>0R-7R(8R)</sub>	Data bus Input/Output
A <sub>0L-12L</sub>	A <sub>0R-12R</sub>	Address Lines
CEL	CER	Chip Enable
OEL	OER	Output Enable
R/WL	R/W <sub>R</sub>	Read/Write Enable
SEML	SEM <sub>R</sub>	Semaphore Enable. When asserted LOW, allows access to eight semaphores. The three least significant bits of the address lines will determine which semaphore to write or read. The I/O <sub>0</sub> pin is used when writing to a semaphore. Semaphores are requested by writing a 0 into the respective location.
INTL	INT <sub>R</sub>	Interrupt Flag. $\overline{INT}_L$ is set when right port writes location 1FFE and is cleared when left port reads location 1FFE. INT <sub>R</sub> is set when left port writes location 1FFF and is cleared when right port reads location 1FFF.
BUSYL	BUSY <sub>R</sub>	Busy Flag
M/S		Master or Slave Select
V <sub>CC</sub>		Power
GND		Ground

### **Selection Guide**

	7C144-15 7C145-15	7C144-25 7C145-25	7C144-35 7C145-35	7C144-55 7C145-55	Unit
Maximum Access Time	15	25	35	55	ns
Maximum Operating Current	220	180	160	160	mA
Maximum Standby Current for I <sub>SB1</sub>	60	40	30	30	mA



## Maximum Ratings<sup>[5]</sup>

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature65°C to +150°C
Ambient Temperature with Power Applied55°C to +125°C
Supply Voltage to Ground Potential0.5V to +7.0V
DC Voltage Applied to Outputs
in High Z State0.5V to +7.0V
DC Input Voltage <sup>[6]</sup> 0.5V to +7.0V

Output Current into Outputs (LOW)	20 mA
Static Discharge Voltage (per MIL-STD-883, Method 3015)	. >2001V
Latch-Up Current	>200 mA

## **Operating Range**

Range	Ambient Temperature	v <sub>cc</sub>
Commercial	0°C to +70°C	$5V\pm10\%$
Industrial	–40°C to +85°C	$5V\pm10\%$

#### Electrical Characteristics Over the Operating Range

					44-15 45-15		44-25 45-25	
Parameter	Description	Test Conditions		Min.	Max.	Min.	Max.	Unit
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = Min., I <sub>OH</sub> = -4.0 mA		2.4		2.4		V
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = Min., I <sub>OL</sub> = 4.0 mA			0.4		0.4	V
V <sub>IH</sub>	Input HIGH Voltage			2.2		2.2		V
V <sub>IL</sub>	Input LOW Voltage				0.8		0.8	V
I <sub>IX</sub>	Input Leakage Current	$GND \leq V_I \leq V_{CC}$		-10	+10	-10	+10	μA
I <sub>OZ</sub>	Output Leakage Current	Outputs Disabled, GND < V <sub>C</sub>	o <u>≺</u> V <sub>CC</sub>	-10	+10	-10	+10	μA
I <sub>CC</sub>	Operating Current	V <sub>CC</sub> = Max., I <sub>OUT</sub> = 0 mA	Com'l		220		180	mA
	Outputs Disabled	Outputs Disabled	Ind				190	
I <sub>SB1</sub>	Standby Current	$\overline{CE}_{I}$ and $\overline{CE}_{R} \ge V_{IH}$ , $C_{I}$	Com'l		60		40	mA
	(Both Ports TTL Levels)	$f = f_{MAX}^{[7]}$	Ind				50	
I <sub>SB2</sub>	Standby Current	$\overline{CE}_{L} \text{ or } \overline{CE}_{R} \ge V_{IH},$ f = f <sub>MAX</sub> <sup>[7]</sup>	Com'l		130		110	mA
	(One Port TTL Level)	$f = f_{MAX}^{L'J}$	Ind				120	
I <sub>SB3</sub>	Standby Current	Both Ports	Com'l		15		15	mA
	(Both Ports CMOS Levels)	$\label{eq:central_constraint} \begin{array}{ c c c } \hline \overline{CE} & and & \overline{CE}_R \geq V_{CC} - 0.2V, \\ \hline V_{IN} \geq V_{CC} - 0.2V \\ or & V_{IN} \leq 0.2V, \ f = 0^{[7]} \end{array}$	Ind				30	
I <sub>SB4</sub>	Standby Current	<u>On</u> e Po <u>rt</u>	Com'l		125		100	mA
	(One Port CMOS Level)	$      \overrightarrow{CE}_{L} \text{ or } \overrightarrow{CE}_{R} \ge V_{CC} - 0.2V, \\ V_{IN} \ge V_{CC} - 0.2V \text{ or } \\ V_{IN} \le 0.2V, \text{ Active } \\ \text{Port Outputs, } f = f_{MAX}^{[7]} $	Ind				115	

Notes:

5. The Voltage on any input or I/O pin cannot exceed the power pin during power-up.6. Pulse width < 20 ns.</li>

7.  $f_{MAX} = 1/t_{RC}$  = All inputs cycling at f = 1/ $t_{RC}$  (except output enable). f = 0 means no address or control lines change. This applies only to inputs at CMOS level standby  $I_{SB3}$ .



### Electrical Characteristics Over the Operating Range (continued)

					44-35 45-35	7C144-55 7C145-55		
Parameter	Description	Test Conditions		Min.	Max.	Min.	Max.	Unit
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = Min., I <sub>OH</sub> = -4.0 mA		2.4		2.4		V
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = Min., I <sub>OL</sub> = 4.0 mA			0.4		0.4	V
V <sub>IH</sub>	Input HIGH Voltage			2.2		2.2		V
V <sub>IL</sub>	Input LOW Voltage				0.8		0.8	V
I <sub>IX</sub>	Input Leakage Current	$GND \leq V_I \leq V_{CC}$		-10	+10	-10	+10	μA
I <sub>OZ</sub>	Output Leakage Current	Outputs Disabled, GND < V	o <u>≺</u> V <sub>CC</sub>	-10	+10	-10	+10	μA
I <sub>CC</sub>	Operating Current	V <sub>CC</sub> = Max., I <sub>OUT</sub> = 0 mA	Com'l		160		160	mA
			Ind		180		180	
I <sub>SB1</sub>	Standby Current	$\overline{CE}_{I}$ and $\overline{CE}_{R} \ge V_{IH}$ , C	Com'l		30		30	mA
	(Both Ports TTL Levels)	$f = \bar{f}_{MAX}^{[7]}$	Ind		40		40	
I <sub>SB2</sub>	Standby Current	$\overline{CE}_{L} \text{ or } \overline{CE}_{R} \ge V_{IH},$ f = f <sub>MAX</sub> <sup>[7]</sup>	Com'l		100		100	mA
	(One Port TTL Level)	$f = f_{MAX}^{I'J}$	Ind		110		110	
I <sub>SB3</sub>	Standby Current	Both Ports	Com'l		15		15	mA
	(Both Ports CMOS Levels)	$\label{eq:central_constraint} \begin{array}{ c c } \hline \overline{CE} & and & \overline{CE}_R \geq V_{CC} - 0.2V, \\ \hline V_{IN} \geq V_{CC} - 0.2V \\ or & V_{IN} \leq 0.2V, \ f = 0^{[7]} \end{array}$	Ind		30		30	
I <sub>SB4</sub>	Standby Current	<u>On</u> e Po <u>rt</u>	Com'l		90		90	mA
	(One Port CMOS Level)		Ind		100		100	

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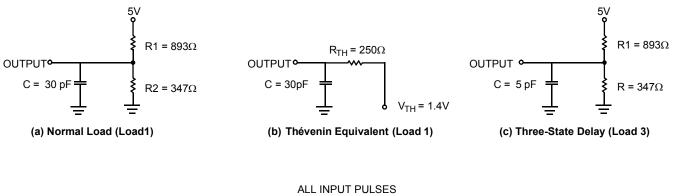
# Capacitance<sup>[8]</sup>

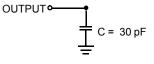
Parameter	Description	Test Conditions	Max.	Unit
C <sub>IN</sub>	Input Capacitance	$T_A = 25^{\circ}C, f = 1 \text{ MHz},$	10	pF
C <sub>OUT</sub>	Output Capacitance	V <sub>CC</sub> = 5.0V	15	pF

Note: 8. Tested initially and after any design or process changes that may affect these parameters.

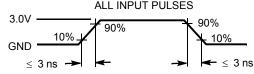


### AC Test Loads and Waveforms









#### Switching Characteristics Over the Operating Range<sup>[9]</sup>

			44-15 45-15	7C144-25 7C145-25		7C144-35 7C145-35		7C144-55 7C145-55		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Unit
READ CYCLE			•							
t <sub>RC</sub>	Read Cycle Time	15		25		35		55		ns
t <sub>AA</sub>	Address to Data Valid		15		25		35		55	ns
t <sub>OHA</sub>	Output Hold From Address Change	3		3		3		3		ns
t <sub>ACE</sub>	CE LOW to Data Valid		15		25		35		55	ns
t <sub>DOE</sub>	OE LOW to Data Valid		10		15		20		25	ns
t <sub>LZOE</sub> <sup>[10, 11,12]</sup>	OE Low to Low Z	3		3		3		3		ns
t <sub>HZOE</sub> <sup>[10, 11,12]</sup>	OE HIGH to High Z		10		15		20		25	ns
t <sub>LZCE</sub> <sup>[10, 11,12]</sup>	CE LOW to Low Z	3		3		3		3		ns
t <sub>HZCE</sub> <sup>[10, 11,12]</sup>	CE HIGH to High Z		10		15		20		25	ns
t <sub>PU</sub> <sup>[12]</sup>	CE LOW to Power-Up	0		0		0		0		ns
t <sub>PD</sub> <sup>[12]</sup>	CE HIGH to Power-Down		15		25		35		55	ns
WRITE CYCLE			•							
t <sub>WC</sub>	Write Cycle Time	15		25		35		55		ns
t <sub>SCE</sub>	CE LOW to Write End	12		20		30		45		ns
t <sub>AW</sub>	Address Set-Up to Write End	12		20		30		45		ns
t <sub>HA</sub>	Address Hold From Write End	2		2		2		2		ns
t <sub>SA</sub>	Address Set-Up to Write Start	0		0		0		0		ns
t <sub>PWE</sub>	Write Pulse Width	12		20		25		40		ns

Notes:

10. At any given temperature and voltage condition for any given device,  $t_{HZCE}$  is less than  $t_{LZCE}$  and  $t_{HZOE}$  is less than  $t_{LZOE}$ .

11. Test conditions used are Load 3.

12. This parameter is guaranteed but not tested.

<sup>9.</sup> Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified I<sub>OI</sub>/I<sub>OH</sub> and 30-pF load capacitance.



# Switching Characteristics $\mbox{Over the Operating Range}^{[9]}$ (continued)

		7C14 7C14	44-15 45-15	7C144-25 7C145-25		7C144-35 7C145-35		7C144-55 7C145-55		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Unit
t <sub>SD</sub>	Data Set-Up to Write End	10		15		15		25		ns
t <sub>HD</sub>	Data Hold From Write End	0		0		0		0		ns
t <sub>HZWE</sub> <sup>[11,12]</sup>	R/W LOW to High Z		10		15		20		25	ns
t <sub>LZWE</sub> <sup>[11,12]</sup>	R/W HIGH to Low Z	3		3		3		3		ns
t <sub>WDD</sub> <sup>[13]</sup>	Write Pulse to Data Delay		30		50		60		70	ns
t <sub>DDD</sub> <sup>[13]</sup>	Write Data Valid to Read Data Valid		25		30		35		40	ns
<b>BUSY TIMING</b>	[14]			1						1
t <sub>BLA</sub>	BUSY LOW from Address Match		15		20		20		30	ns
t <sub>BHA</sub>	BUSY HIGH from Address Mismatch		15		20		20		30	ns
t <sub>BLC</sub>	BUSY LOW from CE LOW		15		20		20		30	ns
t <sub>BHC</sub>	BUSY HIGH from CE HIGH		15		20		20		30	ns
t <sub>PS</sub>	Port Set-Up for Priority	5		5		5		5		ns
t <sub>WB</sub>	R/W LOW after BUSY LOW	0		0		0		0		ns
t <sub>WH</sub>	R/W HIGH after BUSY HIGH	13		20		30		30		ns
t <sub>BDD</sub>	BUSY HIGH to Data Valid		15		25		35		55	ns
INTERRUPT T	IMING <sup>[14]</sup>		•			•	•			
t <sub>INS</sub>	INT Set Time		15		25		25		35	ns
t <sub>INR</sub>	INT Reset Time		15		25		25		35	ns
SEMAPHORE	TIMING									
t <sub>SOP</sub>	SE <u>M Flag</u> Update Pulse (OE or SEM)	10		10		15		20		ns
t <sub>SWRD</sub>	SEM Flag Write to Read Time	5		5		5		5		ns
t <sub>SPS</sub>	SEM Flag Contention Window	5		5		5		5		ns

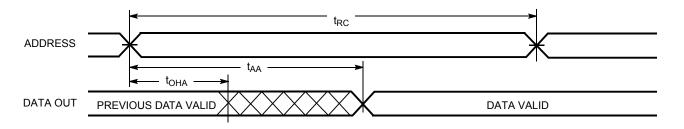
Notes:

For information on part-to-part delay through RAM cells from writing port to reading port, refer to Read Timing with Port-to-Port Delay waveform.
 Test conditions used are Load 2.

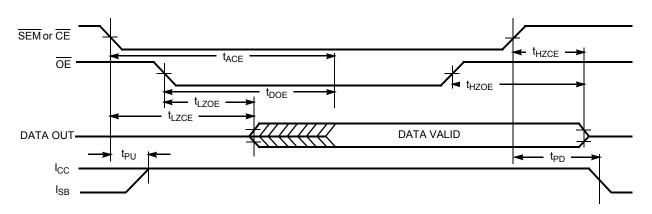


#### Switching Waveforms

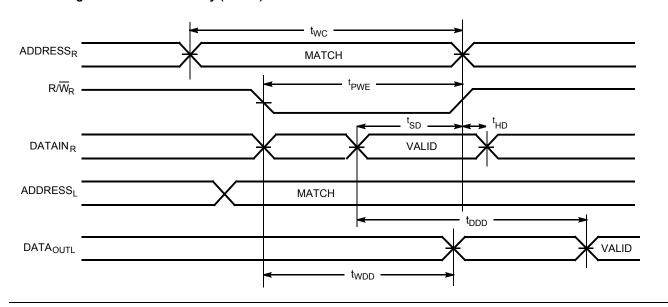
Read Cycle No. 1 (Either Port Address Access)<sup>[15, 16]</sup>



Read Cycle No. 2 (Either Port CE/OE Access)<sup>[15, 17, 18]</sup>



## Read Timing with Port-to-Port Delay (M/S=L)<sup>[19, 20]</sup>



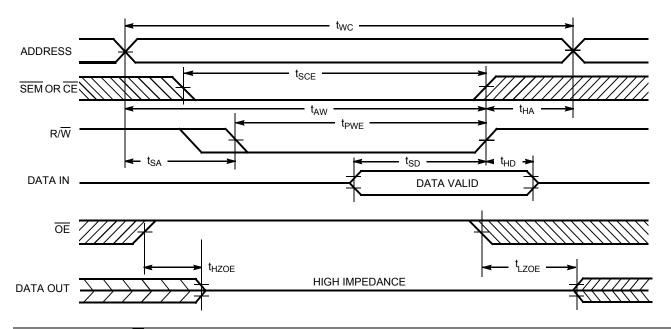
#### Notes:

15. R/W is HIGH for read cycle.

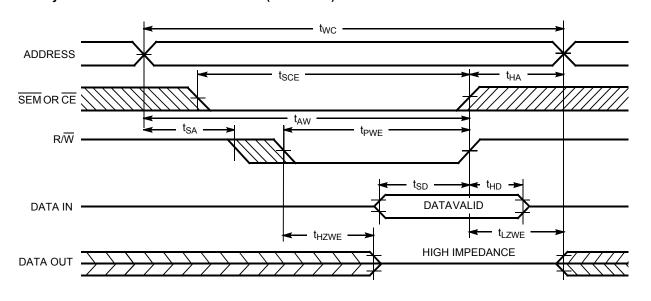
<sup>15.</sup> K/W IS HIGH for read cycle. 16. Device is continuously selected  $\overline{CE} = LOW$  and  $\overline{OE} = LOW$ . This waveform cannot be used for semaphore reads. 17. Address valid prior to or coincident with  $\overline{CE}$  transition LOW. 18.  $\overline{OE}_L = L$ , SEM = H when accessing RAM.  $\overline{CE} = H$ , SEM = L when accessing semaphores. 19.  $\overline{BUSY} = HIGH$  for the writing port. 20.  $\overline{CE}_L = \overline{CE}_R = LOW$ .



Write Cycle No. 1: OE Three-State Data I/Os (Either Port)<sup>[21, 22, 23]</sup>



Write Cycle No. 2: R/W Three-State Data I/Os (Either Port)<sup>[21, 23, 24]</sup>



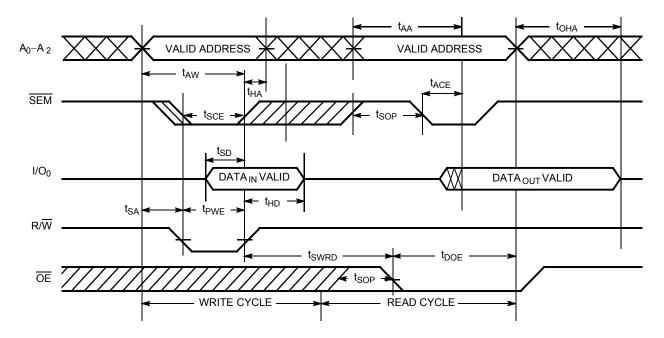
Notes:

24. Data I/O pins enter high impedance when OE is held LOW during write.

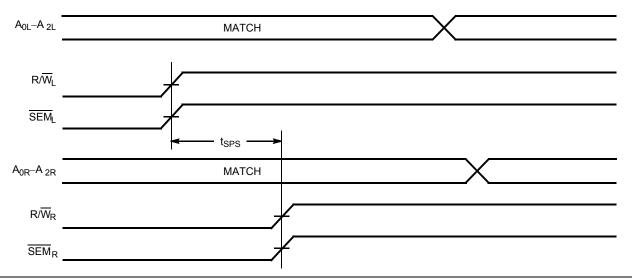
<sup>Notes:
21. The internal write time of the memory is defined by the overlap of CE or SEM LOW and R/W LOW. Both signals must be LOW to initiate a write, and either signal can terminate a write by going HIGH. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.
22. If OE is LOW during a R/W controlled write cycle, the write pulse width must be the larger of t<sub>PWE</sub> or (t<sub>HZWE</sub> + t<sub>SD</sub>) to allow the I/O drivers to turn off and data to be placed on the bus for the required t<sub>SD</sub>. If OE is HIGH during a R/W controlled write cycle (as in this example), this requirement does not apply and the write pulse can be as short as the specified t<sub>PWE</sub>.
23. R/W must be HIGH during all address transitions.
24. Dots the puts be the log action by the log is held to log during a mit.</sup> 



Semaphore Read After Write Timing, Either Side<sup>[25]</sup>



Semaphore Contention<sup>[26, 27, 28]</sup>



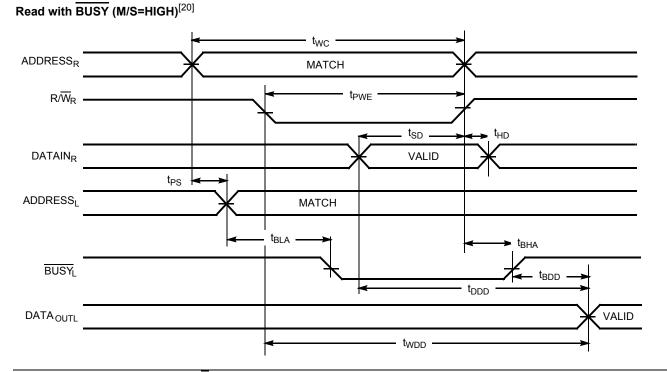
Notes: 25. CE = HIGH for the duration of the above timing (both write and read cycle).

26. I/O<sub>0R</sub> = I/O<sub>0L</sub> = LOW (request semaphore);  $\overline{CE}_{R} = \overline{CE}_{L}$  = HIGH

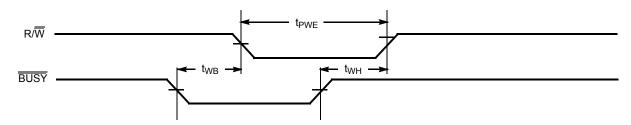
27. Semaphores are reset (available to both ports) at cycle start.

28. If t<sub>SPS</sub> is violated, the semaphore will definitely be obtained by one side or the other, but there is no guarantee which side will control the semaphore.



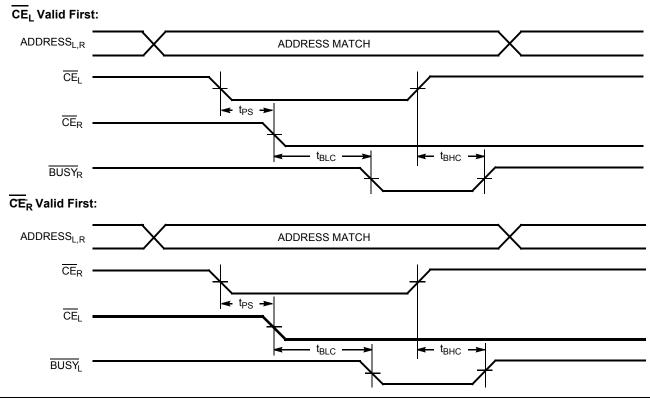


## Write Timing with Busy Input (M/S=LOW)

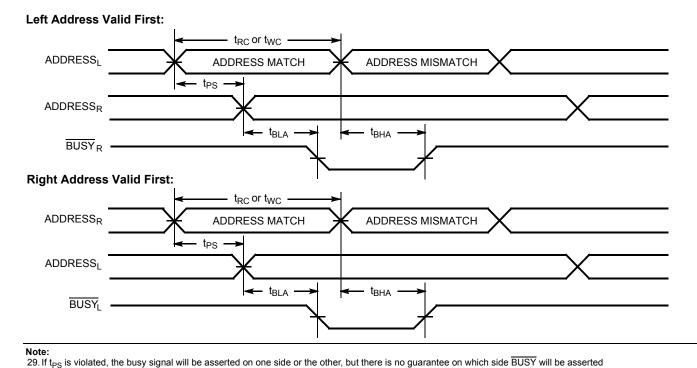




Busy Timing Diagram No. 1 (CE Arbitration)<sup>[29]</sup>



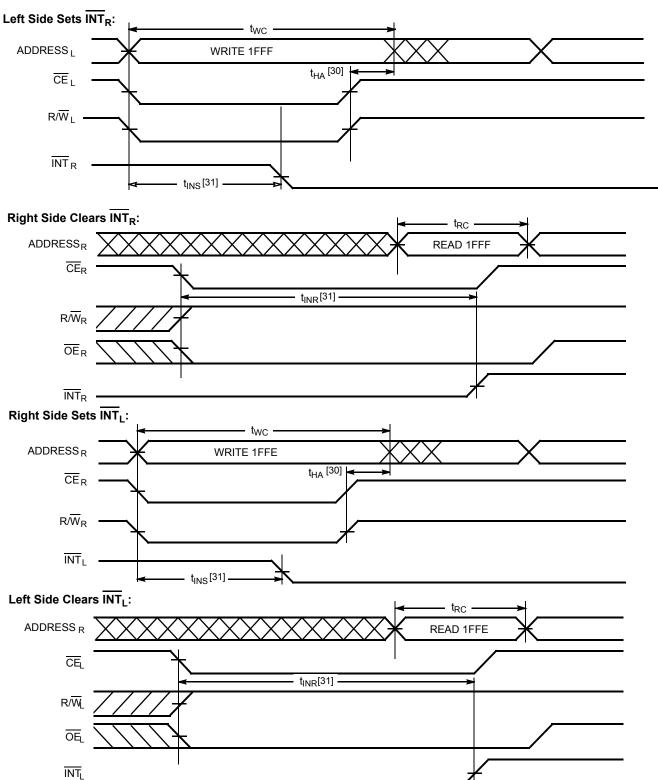
## Busy Timing Diagram No. 2 (Address Arbitration)<sup>[29]</sup>



#### Document #: 38-06034 Rev. \*C



#### **Interrupt Timing Diagrams**



#### Notes:

30. t<sub>HA</sub> depends on which enable pin ( $\overline{CE}_L$  or  $\underline{R/W}_L$ ) is deasserted first. 31. t<sub>INS</sub> or t<sub>INR</sub> depends on which enable pin ( $\overline{CE}_L$  or  $\overline{R/W}_L$ ) is asserted last.



The CY7C144/5 consists of a an array of 8K words of 8/9 bits each of <u>dual-port RAM</u> cells, I/O and address lines, and control signals (CE, OE, R/W). These control pins permit independent access for reads or writes to any location in memory. To handle simultaneous writes/reads to the same location, a BUSY pin is provided on each port. Two interrupt (INT) pins can be utilized for port-to-port communication. Two semaphore (SEM) control pins are used for allocating shared resources. With the M/S pin, the CY7C144/5 can function as a Master (BUSY pins are outputs) or as a slave (BUSY pins are inputs). The CY7C144/5 has an automatic power-down feature controlled by CE. Each port is provided with its own output enable control (OE), which allows data to be read from the device.

### **Functional Description**

#### Write Operation

Data <u>m</u>ust be set up for a duration of  $t_{SD}$  before the rising edge of R/W in order to guarante<u>e</u> a valid write. A write operation is controlled by either the OE pin (see Write Cycle No.1 waveform) or the R/W pin (see Write Cycle No. 2 waveform). Data can be written to the device  $t_{HZOE}$  after the OE is deasserted or  $t_{HZWE}$  after the falling edge of R/W. Required inputs for non-contention operations are summarized in *Table 1*.

If a location is being written to by one port and the opposite port attempts to read that location, a port-to-port flowthrough delay must be met before the data is read on the output; otherwise the data read is not deterministic. Data will be valid on the port  $t_{DDD}$  after the data is presented on the other port.

#### **Read Operation**

Whe<u>n</u> reading the device, the user must assert both the  $\overline{OE}$ and  $\overline{CE}$  pins. Data will be available t<sub>ACE</sub> after  $\overline{CE}$  or t<sub>DOE</sub> after  $\overline{OE}$  are asserted. If the user of the CY7C144/5 wishes to access a semaphore flag, then the SEM pin must be asserted instead of the CE pin.

#### Interrupts

The interrupt flag (INT) permits communications between ports. When the left port writes to location 1FFF, the right port's interrupt flag (INT<sub>R</sub>) is set. This flag is cleared when the right port reads that same location. Setting the left port's interrupt flag (INT<sub>L</sub>) is accomplished when the right port writes to location 1FFE. This flag is cleared when the left port reads location 1FFE. The message at 1FFF or 1FFE is user-defined. See *Table 2* for input requirements for INT. INT<sub>R</sub> and INT<sub>L</sub> are push-pull outputs and do not require pull-up resistors to operate.

#### Busy

The CY7C144/5 provides on-chip arbitration to alleviate simultaneous memory location access (contention). If both ports' CEs are asserted and an address match occurs within t<sub>PS</sub> of each other the Busy logic will determine which port has access. If t<sub>PS</sub> is violated, one port will definitely gain permission to the location, but it is not guaranteed which one. BUSY will be asserted t<sub>BLA</sub> after an address match or t<sub>BLC</sub> after CE is taken LOW. BUSY<sub>L</sub> and BUSY<sub>R</sub> in master mode are push-pull outputs and do not require pull-up resistors to operate.

#### Master/Slave

An M/S pin is provided in order to expand the word width by configuring the device as either a master or <u>a slave</u>. The BUSY output of the master is connected to the BUSY input of the slave. This will allow the device to interface to a master device with no external components. Writing of slave devices must be delayed until after the BUSY input has settled. Otherwise, the slave chip may begin a write cycle during a contention situation. When presented a HIGH input, the M/S pin allows the device to be used as a master and therefore the BUSY line is an output. BUSY can then be used to send the arbitration outcome to a slave.

#### **Semaphore Operation**

The CY7C144/5 provides eight semaphore latches which are separate from the dual-port memory locations. Semaphores are used to reserve resources that are shared between the two ports. The state of the semaphore indicates that a resource is in use. For example, if the left port wants to request a given resource, it sets a latch by writing a 0 to a semaphore location. The left port then verifies its success in setting the latch by reading it. After writing to the semaphore, SEM or OE must be deasserted for  $t_{SOP}$  before attempting to read the semaphore. The semaphore value will be available  $t_{SWRD}$  +  $t_{DOE}$  after the rising edge of the semaphore write. If the left port was successful (reads a 0), it assumes control over the shared resource, otherwise (reads a 1) it assumes the right port has control and continues to poll the semaphore.When the right side has relinquished control of the semaphore (by writing a 1), the left side will succeed in gaining control of the semaphore. If the left side no longer requires the semaphore, a 1 is written to cancel its request.

Semaphores are accessed by asserting  $\overline{SEM}$  LOW. The  $\overline{SEM}$  pin functions as a chip enable for the semaphore latches ( $\overline{CE}$  must remain HIGH during  $\overline{SEM}$  LOW). A<sub>0-2</sub> represents the semaphore address.  $\overline{OE}$  and  $\overline{RW}$  are used in the same manner as a normal memory access. When writing or reading a semaphore, the other address pins have no effect.

When writing to the semaphore, only  $I/O_0$  is used. If a 0 is written to the left port of an unused semaphore, a 1 will appear at the same semaphore address on the right port. That semaphore can now only be modified by the side showing 0 (the left port in this case). If the left port now relinquishes control by writing a 1 to the semaphore, the semaphore will be set to 1 for both sides. However, if the right port had requested the semaphore (written a 0) while the left port had control, the right port would immediately own the semaphore as soon as the left port released it. *Table 3* shows sample semaphore operations.

When reading a semaphore, all eight/nine data lines output the semaphore value. The read value is latched in an output register to prevent the semaphore from changing state during a write from the other port. If both ports attempt to access the semaphore within  $t_{SPS}$  of each other, the semaphore will definitely be obtained by one side or the other, but there is no guarantee which side will control the semaphore.

Initialization of the semaphore is not automatic and must be reset during initialization program at power-up. All Semaphores on both sides should have a one written into them at initialization from both sides to assure that they will be free when needed.



#### Table 1. Non-Contending Read/Write

	In	puts		Outputs	
CE	R/W	OE	SEM	I/O <sub>0-7/8</sub>	Operation
Н	Х	Х	Н	High Z	Power-Down
Н	Н	L	L	Data Out	Read Data in Semaphore
Х	Х	Н	Х	High Z	I/O Lines Disabled
Н		Х	L	Data In	Write to Semaphore
L	Н	L	Н	Data Out	Read
L	L	Х	Н	Data In	Write
L	Х	Х	L		Illegal Condition

# Table 2. Interrupt Operation Example (assumes $\overline{\text{BUSY}}_{\text{L}} = \overline{\text{BUSY}}_{\text{R}} = \text{HIGH}$ )

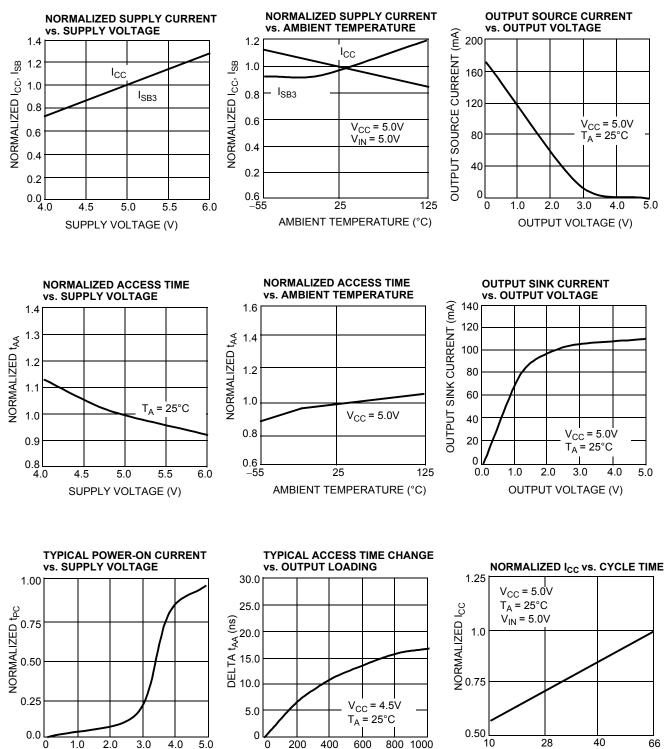
	Left Port					Right Port				
Function	R/W	CE	OE	A <sub>0-12</sub>	INT	R/W	CE	OE	A <sub>0-12</sub>	INT
Set Left INT	Х	Х	Х	Х	L	L	L	Х	1FFE	Х
Reset Left INT	Х	L	L	1FFE	Н	Х	L	L	Х	Х
Set Right INT	L	L	Х	1FFF	Х	Х	Х	Х	Х	L
Reset Right INT	Х	Х	Х	Х	Х	Х	L	L	1FFF	Н

#### Table 3. Semaphore Operation Example

Function	I/O <sub>0-7/8</sub> Left	I/O <sub>0-7/8</sub> Right	Status
No action	1	1	Semaphore free
Left port writes semaphore	0	1	Left port obtains semaphore
Right port writes 0 to semaphore	0	1	Right side is denied access
Left port writes 1 to semaphore	1	0	Right port is granted access to semaphore
Left port writes 0 to semaphore	1	0	No change. Left port is denied access
Right port writes 1 to semaphore	0	1	Left port obtains semaphore
Left port writes 1 to semaphore	1	1	No port accessing semaphore address
Right port writes 0 to semaphore	1	0	Right port obtains semaphore
Right port writes 1 to semaphore	1	1	No port accessing semaphore
Left port writes 0 to semaphore	0	1	Left port obtains semaphore
Left port writes 1 to semaphore	1	1	No port accessing semaphore



## **Typical DC and AC Characteristics**



CAPACITANCE (pF)

SUPPLY VOLTAGE (V)

CYCLE FREQUENCY (MHz)



# **Ordering Information**

#### 8K x8 Dual-Port SRAM

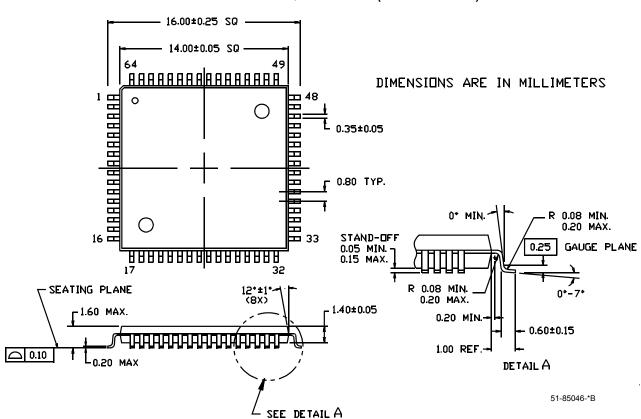
Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range	
15	CY7C144-15AC	A65	64-Lead Thin Quad Flat Pack	Commercial	
	CY7C144-15AXC	A65	64-Lead Pb-Free Thin Quad Flat Pack	_	
	CY7C144-15JC	J81	68-Lead Plastic Leaded Chip Carrier	_	
	CY7C144-15JXC	J81	68-Lead Pb-Free Plastic Leaded Chip Carrier	1	
	CY7C144-15AI	A65	64-Lead Thin Quad Flat Pack	Industrial	
	CY7C144-15AXI	A65	64-Lead Pb-Free Thin Quad Flat Pack		
25	CY7C144-25AC	A65	64-Lead Thin Quad Flat Pack	Commercial	
	CY7C144-25AXC	A65	64-Lead Pb-Free Thin Quad Flat Pack		
	CY7C144-25JC	J81	68-Lead Plastic Leaded Chip Carrier		
	CY7C144-25AI	A65	64-Lead Thin Quad Flat Pack	Industrial	
	CY7C144-25JI	J81	68-Lead Plastic Leaded Chip Carrier	1	
35	CY7C144-35AC	A65	64-Lead Thin Quad Flat Pack	Commercial	
	CY7C144-35JC	J81	68-Lead Plastic Leaded Chip Carrier		
	CY7C144-35AI	A65	64-Lead Thin Quad Flat Pack	Industrial	
	CY7C144-35JI J81 68-Lead Plastic Leaded Chip		68-Lead Plastic Leaded Chip Carrier		
55	CY7C144-55AC	A65	64-Lead Thin Quad Flat Pack	Commercial	
	CY7C144-55AXC	A65	64-Lead Pb-Free Thin Quad Flat Pack		
	CY7C144-55JC	J81	68-Lead Plastic Leaded Chip Carrier		
	CY7C144-55JXC	J81	68-Lead Pb-Free Plastic Leaded Chip Carrier		
	CY7C144-55AI	A65	64-Lead Thin Quad Flat Pack	Industrial	
	CY7C144-55JI	J81	68-Lead Plastic Leaded Chip Carrier		

#### 8K x9 Dual-Port SRAM

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range	
15	CY7C145-15AC	A80	80-Lead Thin Quad Flat Pack	Commercial	
	CY7C145-15AXC	A80	80-Lead Pb-Free Thin Quad Flat Pack		
	CY7C145-15JC	J81	68-Lead Plastic Leaded Chip Carrier	_	
25	CY7C145-25AC	A80	80-Lead Thin Quad Flat Pack	Commercial	
	CY7C145-25JC	J81	68-Lead Plastic Leaded Chip Carrier		
	CY7C145-25AI	A80	80-Lead Thin Quad Flat Pack	Industrial	
	CY7C145-25JI	J81	68-Lead Plastic Leaded Chip Carrier		
35	CY7C145-35AC	A80	80-Lead Thin Quad Flat Pack	Commercial	
	CY7C145-35JC	J81	68-Lead Plastic Leaded Chip Carrier		
	CY7C145-35JXC	J81	68-Lead Pb-Free Plastic Leaded Chip Carrier		
	CY7C145-35AI	A80	80-Lead Thin Quad Flat Pack	Industrial	
	CY7C145-35JI	J81	68-Lead Plastic Leaded Chip Carrier	7	
55	CY7C145-55AC	A80	80-Lead Thin Quad Flat Pack	Commercial	
	CY7C145-55JC	J81	68-Lead Plastic Leaded Chip Carrier	1	
	CY7C145-55AI	A80	80-Lead Thin Quad Flat Pack	Industrial	
	CY7C145-55JI	J81	68-Lead Plastic Leaded Chip Carrier	1	



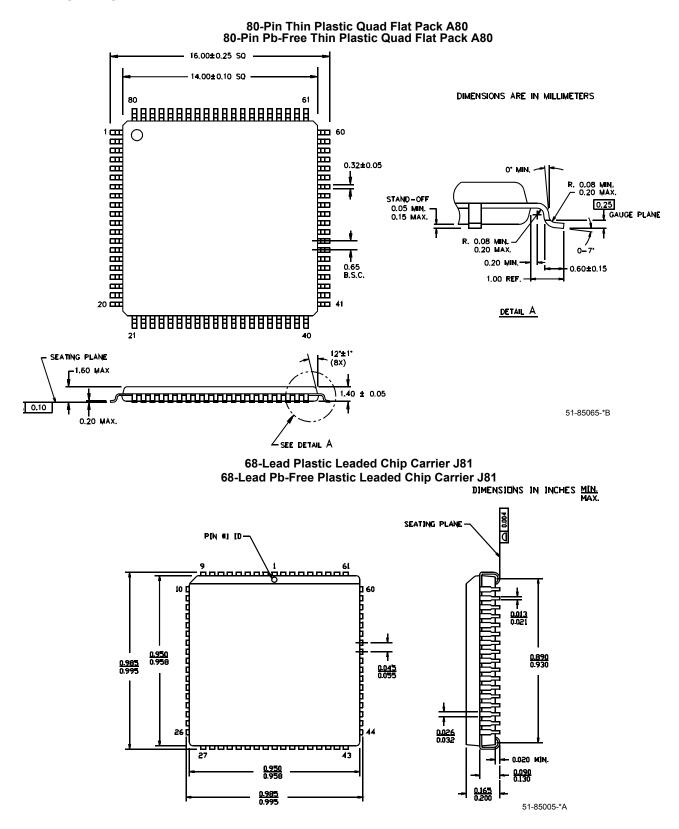
Package Diagrams



64-Lead Thin Plastic Quad Flat Pack (14 x 14 x 1.4 mm) A65 64-Lead Pb-Free Thin Plastic Quad Flat Pack (14 x 14 x 1.4 mm) A65



## Package Diagrams (continued)



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# **Document History Page**

Document Title: CY7C145, CY7C144 8K x 8/9 Dual-Port Static RAM with Sem, Int, Busy Document Number: 38-06034				
REV.	ECN NO.	lssue Date	Orig. of Change	Description of Change
**	110175	09/29/01	SZV	Change from Spec number: 38-00163 to 38-06034
*A	122285	12/27/02	RBI	Power up requirements added to Maximum Ratings Information
*В	236752	See ECN	YDT	Removed cross information from features section, added CY7C144-15AI to ordering information section
*C	393320	See ECN	YIM	Added Pb-Free Logo Added Pb-Free parts to ordering information: CY7C144-15AXC, CY7C144-15JXC, CY7C144-15AXI, CY7C144-25AXC, CY7C144-55AXC, CY7C144-55JXC, CY7C145-15AXC, CY7C145-35JXC